

BS EN 62047-18:2013



BSI Standards Publication

Semiconductor devices — Micro-electromechanical devices

Part 18: Bend testing methods
of thin film materials

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National foreword

This British Standard is the UK implementation of EN 62047-18:2013. It is identical to IEC 62047-18:2013.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Published by BSI Standards Limited 2013

ISBN 978 0 580 72011 6
ICS 31.080.99

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 31 October 2013.

Amendments/corrigenda issued since publication

Date	Text affected
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